

DATA SHEET

L 67132/L 67142

2 K x 8 CMOS DUAL PORT RAM 3.3 VOLT

FEATURES

- SINGLE 3.3 V \pm 0.3 VOLT POWER SUPPLY
- FAST ACCESS TIME 45(*) NS TO 70 NS
- 67132L/67142L LOW POWER
 67132V/67142V VERY LOW POWER
- EXPANDABLE DATA BUS TO 16 BITS OR MORE USING MASTER/SLAVE DEVICES WHEN USING MORE THAN ONE DEVICE
- (*) Preliminary

- ON CHIP ARBITRATION LOGIC
- BUSY OUTPUT FLAG ON MASTER
- **BUSY INPUT FLAG ON SLAVE**
- FULLY ASYNCHRONOUS OPERATION FROM EITHER PORT
- BATTERY BACKUP OPERATION: 2 V DATA RETENTION

INTRODUCTION

The L 67132/67142 are very low power CMOS dual port static RAMs organized as 2048 x 8. They are designed to be used as a stand-alone 8 bit dual port RAM or as a combination MASTER/SLAVE dual port for 16 bits or more width systems. The MHS MASTER/SLAVE dual port approach in memory system applications results in full speed, error free operation without the need for additional discrete logic.

Master and slave devices provide two independent ports with separate control, address and I/O pins that permit independent, asynchronous access for reads and writes to any location in the memory. An automatic power down feature controlled by CS permits the onchip circuitry of each port in order to enter a very low stand by power mode.

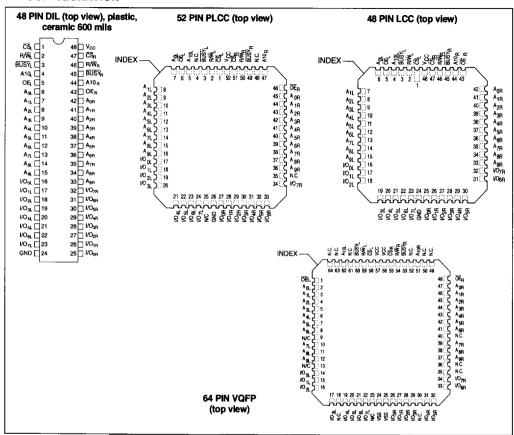
Using an array of eight transistors (8T) memory cell and fabricated with the state of the art 1.0 μm lithography named SCMOS, the L67132/142 combine an extremely low standby supply current (typ = 1.0 μA) with a fast access time at 45 ns over the full temperature range. All versions offer battery backup data retention capability with a typical power consumption at less than 5 μW .

For military/space applications that demand superior levels of performance and reliability the L 67132/142 is processed according to the methods of the latest revision of the MIL STD 883 (class B or S) and/or ESA SCC 9000.

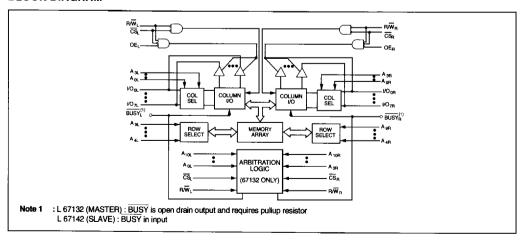
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INTERFACE

PIN CONFIGURATION



BLOCK DIAGRAM





PIN NAMES

LEFT PORT	RIGHT PORT	NAMES
CSL	CS _R	Chip select
R/W _L	R/W _R	Write Enable
<u>ŌĒ</u> L	OE _R	Output Enable
A0L - 10L	A0R - 10R	Address
I/O _{0L - 7L}	I/O _{0R - 7R}	Data Input/Output
BUSYL	BUSYR	Busy Flag
V	CC	Power
G	ND	Ground

FUNCTIONAL DESCRIPTION

The L 67132/L67142 has two ports with separate control, address and I/0 pins that permit independent read/write access to any memory location. These devices have an automatic power-down feature controlled by CS. CS controls on-chip power-down circuitry which causes the port concerned to go into stand-by mode when not selected (CS high). When a port is selected access to the full memory array is permitted. Each port has its own Output Enable control (OE). In read mode, the port's OE turns the Output drivers on when set LOW. Non-conflicting READ/WRITE conditions are illustrated in table 1

ARBITRATION LOGIC

The arbitration logic will resolve an address match or a chip select match down to a minimum of 5 ns and determine which port has access. In all cases, an active BUSY flag will be set for the inhibited port.

The BUSY flags are required when both ports attempt to access the same location simultaneously. Should this conflict arise, on-chip arbitration logic will determine which port has access and set the BUSY flag for the inhibited port. BUSY is set at speeds that allow the processor to hold the operation with its associated address and data. It should be noted that the operation is invalid for the port for which BUSY is set LOW. The inhibited port will be given access when BUSY goes inactive.

A conflict will occur when both left and right ports are active and the two addresses coincide. The on-chip arbitration determines access in these circumstances. Two modes of arbitration are provided: (1) if the addresses match and are valid before \overline{CS} on-chip control logic arbitrates between \overline{CS}_L and \overline{CS}_R for access; or (2) if the \overline{CS} are low before an address match, on-chip control logic arbitrates between the left

and right addresses for access (refer to table 2). The inhibited port's BUSY flag is set and will reset when the port granted access completes its operation in both arbitration modes.

DATA BUS WIDTH EXPANSION

MASTER/SLAVE DESCRIPTION

Expanding the data bus width to 16 or more bits in a dual-port RAM system means that several chips may be active simultaneously. If every chip has a hardware arbitrator, and the addresses for each chip arrive at the same time one chip may activate its L BUSY signal while another activates its R BUSY signal. Both sides are now busy and the CPUs will wait indefinitely for their port to become free.

To overcome this "Busy Lock-Out" problem, MHS has developed a MASTER/SLAVE system which uses a single hardware arbitrator located on the MASTER. The SLAVE has BUSY inputs which allow direct interface to the MASTER with no external components, giving a speed advantage over other systems.

When dual-port RAMs are expanded in width, the SLAVE RAMs must be prevented from writing until the BUSY input has been settled. Otherwise, the SLAVE chip may begin a write cycle during a conflict situation. On the opposite, the write pulse must extend a hold time beyond BUSY to ensure that a write cycle occurs once the conflict is resolved. This timing is inherent in all dual-port memory systems where more than one chip is active at the same time.

The write pulse to the SLAVE must be inhibited by the MASTER's maximum arbitration time. If a conflict then occurs, the write to the SLAVE will be inhibited because of the MASTER's BUSY signal.

TRUTH TABLE

Table 1: Non contention read/write control .(4)

LEFT OR RIGHT PORT(1)		PORT ⁽¹⁾	FUNCTION					
R/W	CS	ŌĒ	D0-7	FUNCTION				
Х	X H X Z Po		Z	Port Disabled and in Power Down Mode. ICCSB or ICCSB1				
L	L	Х	DATAIN	Data on Port Written into memory ⁽²⁾				
Н	L	L	DATA _{OUT}	Data in Memory Output on Port ⁽³⁾				
Н	L	Н	Z	High Impedance Outputs				

Notes: 1. A_{OL} - A_{10L} ≠ A_{0R} - A_{10R}. 2. If BUSY = L, data is not written.

2. If BUSY = L, data may not be valid, see t_{WDD} and t_{DDD} timing. 4. H = HIGH, L = LOW, X = DON'T CARE, Z = HIGH IMPEDANCE.

Table 2: Arbitration. (5)

LEFT	PORT	RIGH"	F PORT	FLA	GS	FUNCTION
CSL	A _{0L} - A _{10L}	CSR	A _{0L} - A _{10R}	BUSYL	BUSYR	FUNCTION
Н	Х	Н	Х	Н	Н	No Contention
L	Any	Н	Х	Н	Н	No Contention
Н	Х	L	Any	Н	Н	No Contention
L	≠ A _{0R} - A _{10R}	L	≠ A _{0L} - A _{10L}	Н	Н	No Contention
ADDRESS ARBITRATION WITH CE LOW BEFORE ADDRESS MATCH					СН	-
L	LV5R	L	LV5R	Н	L	L-Port Wins
L	RV5L	L	RV5L	Ĺ	Н	R-Port Wins
L	Same	L	Same	Н	L	Arbitration Resolved
L	Same	L	Same	L	Н	Arbitration Resolved
CS ARBITE	ATION WITH A	DDRESS MA	TCH BEFORE	CS		
LL5R	= A _{0R} - A _{10R}	LL5R	$= A_{0L} - A_{10L}$	Н	L	L-Port Wins
RL5L	= A _{0R} - A _{10R}	RL5L	= A _{0L} - A _{10L}	L	Н	R-Port Wins
LW5R	= A _{0R} - A _{10R}	LW5R	= A _{0L} - A _{10L}	Н	L	Arbitration Resolved
LW5R	= A _{0R} - A _{10R}	LW5R	= A _{0L} - A _{10L}	L	Н	Arbitration Resolved

Notes: 5. X = DON'T CARE, L = LOW, H = HIGH.

LV5R = Left Address Valid ≥ 5 ns before right address.

RV5L = Right Address Valid ≥ 5 ns before left address.

Same = Left and Right Addresses match within 5 ns of each other.

LL5R = Left \overline{CS} = LOW \geq 5 ns before Right \overline{CS} .

RL5L = Right CS = LOW ≥ 5 ns before left CS.

LW5R = Left and Right \overline{CS} = LOW within 5 ns of each other.

ELECTRICAL CHARACTERISTICS

ABSOLUTE MAXIMUM RATINGS

Supply voltage (VCC-GND):

-0.3 V to 7.0 V

Input or output voltage applied:

(GND - 0.3 V) to (VCC + 0.3 V)

Storage temperature:

- 65 °C to + 150 °C

* Notice

Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extented periods may affect reliability.

OPERATING RANGE	OPERATING SUPPLY VOLTAGE	OPERATING TEMPERATURE
Military	$V_{CC} = 3.3 \text{ V} \pm 0.3 \%$	-55 °C to + 125 °C
Automotive	$V_{CC} = 3.3 \text{ V} \pm 0.3 \%$	- 40 °C to + 125 °C
Commercial	$V_{CC} = 3.3 \text{ V} \pm 0.3 \%$	0 °C to + 70 °C
Industrial	$V_{CC} = 3.3 \text{ V} \pm 0.3 \%$	-40 °C to + 85 °C

DC PARAMETERS

			L67132/ 142-45		L67132/ 142-55		L67132/ 142-70			
PARAMETER	DESCRIPTION	VERSION	сом	IND MIL AUTO	сом	IND MIL AUTO	сом	IND MIL AUTO	UNIT	VALUE
			PRELI	MINARY		7010		70.0		
ICCSB (6)	Standby supply current	V	1	1	1	1	1	1	mA	Max
ICCSB (6)	(Both ports TTL level inputs)	L	5	10	5	10	5	10	mA	Max
IccsB1 (7)	Standby supply current	V	10	20	10	20	10	20	μА	Max
ICCSB1 (7)	(Both ports CMOS level inputs)	L	100	200	100	200	100	200	μА	Max
ICCOP (8)	Operating supply current	V	80	90	70	80	60	70	mA	Max
ICCOP (8)	Standby supply current (Both ports TTL level inputs) Standby supply current (Both ports CMOS level inputs) Operating supply current (Both ports active) Operating supply current	L	80	100	70	90	60	80	mA	Max
Operating supply current		V	50	55	40	45	35	40	mA	Max
ICCOP 1 (9)	(One port active - One port standby)	L	60	65	50	55	45	50	mA	Max

Notes: 6. $\overline{CS}_L = \overline{CS}_R \ge 2.2 \text{ V}.$

7. CS_L = CS_R ≥ VCC - 0.2 V.

8. Both ports active – Maximum frequency – Outputs open – \overline{OE} = VIH.

9. One port active (f = fMAX) – Output open – One port stand-by TTL or CMOS Level inputs – CS_L = CS_R ≥ 2.2 V.

PARAMETER	DESCRIPTION	L67132-45/55/70 L67142-45/55/70	UNIT	VALUE
II/O ₍₁₀₎	Input/Output leakage current	± 10	μА	Max
VIL ₍₁₁₎	Input low voltage	0.7	V	Max
VIH ₍₁₁₎	Input high voltage	1.8	٧	Min
VOL(12)	Output low voltage (I/O ₀ -I/O ₇)	0.5	٧	Max
VOL ₍₁₃₎	Open drain output low voltage (BUSY)	0.5	V	Max
VOH ₍₁₂₎	Output high voltage	1.5	V	Min
C IN(17)	Input capacitance	5	pF	Max
C OUT(17)	Output capacitance	7	pF	Max

Notes: 10. $V_{CC} = 5.5 \text{ V}$, $V_{IR} = G_{IR} \text{ for } V_{CC}$, $\overline{CS} = VIH$, $V_{OU} = 0$ to V_{CC} .

11. VIH max = V_{CC} + 0.3 V, VIL min - 0.3 V or - 1 V pulse width 50 ns.

12. V_{CC} min, IOL = 4 mA, IOH = -4 mA.

13. $l_{OL} = 16 \text{ mA}$.

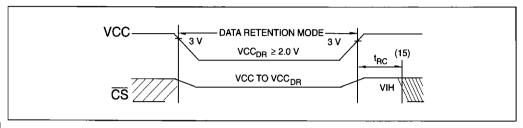


DATA-RETENTION MODE

MHS CMOS RAMs are designed with battery backup in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules insure data retention:

- 1 Chip select $(\overline{\text{CS}})$ must be held high during data retention ; within Vcc to VCC_{DR}.
- 2 $\overline{\text{CS}}$ must be kept between V_{CC} 0.2 V and 70 % of V_{CC} during the power up and power down transitions.
- 3 The RAM can begin operation > tRC after Vcc reaches the minimum operating voltage (3 volts).

TIMING



PARAMETER	TEST CONDITION	IS (14)	М	UNIT	
			сом	MIL IND AUTO	
ICC _{DR1}	@ VCC _{DR} = 2 V	V L	10 100	20 200	μА

Notes : 14. $\overline{CS} = V_{CC}$, Vin = Gnd to V_{CC} .

AC TEST CONDITIONS

Input Pulse Levels : GND to 3.0 V

Input Rise/Fall Times : 5 ns Input Timing Reference Levels : 1.5 V

Figure 1: Output Load.

Output Reference Levels : 1.5 V

Output Load

: see figures 1, 2

5V 1250 Ω 775 Ω 5 pF*

Figure 2 : Output Load. (For thz, tuz, twz, and tow)

AC PARAMETERS

READ CYCLE		PARAMETER	L 67132-45 L 67142-45		L 67132-55 L 67142-55		L 67132-70 L 67142-70		UNIT
SYMBOL (19)	SYMBOL (20)		MIN. PRELI	MAX. MINARY	MIN.	MAX.	MIN.	MAX.	
TAVAVR	t _{RC}	Read cycle time	45	_	55	_	70	_	ns
TAVQV	taa	Address access time	_	45	-	55	_	70	ns
TELQV	tacs	Chip Select access time (18)	-	45	_	55	-	70	ns
TGLQV	tAOE	Output enable access time	_	30	_	35	_	40	ns
TAVQX	tон	Output hold from address change	0	_	0		0	_	ns
TELQZ	tız	Output low Z time (16, 17)	5	_	5	_	5	_	ns
TEHQZ	t _{HZ}	Output high Z time (16, 17)	_	20	-	30	_	35	ns
TPU	t _{PU}	Chip Select to power up time (17)	0	_	0	_	0	-	ns
TPD	t _{PD}	Chip disable to power down time (17)	_	50	_	50	_	50	ns

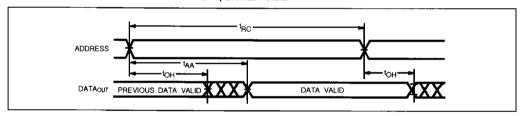
Notes: 16. Transition is measured \pm 500 mV from low or high impedance voltage with load (figures 1 and 2).

This parameter is guaranteed but not tested.
 To access RAM CS = VIL.

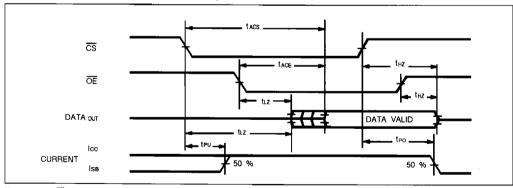
19. STD symbol.

20. ALT sýmbol.

TIMING WAVEFORM OF READ CYCLE NO. 1, EITHER SIDE (21, 22, 24)



TIMING WAVEFORM OF READ CYCLE NO. 2, EITHER SIDE (21, 23, 25)



Notes: 21. R/W is high for read cycles.

22. Device is continuously enabled, CS = VIL.

23. Addresses valid prior to or coincident with CS transition low.

24. OE = V_{IL}

25. To access RAM, CS = VIL.



AC PARAMETERS

WRITE CYCLE		PARAMETER	L 67132-45 L 67142-45		L 67132-55 L 67142-55		L 67132-70 L 67142-70		UNIT
SYMBOL (30)	SYMBOL (31)		MIN. PRELII	MAX. MINARY	MIN.	MAX.	MIN.	MAX.	
TAVAVW	twc	Write cycle time	45	_	55		70	-	ns
TELWH	tsw	Chip select to end of write (28)	35	-	40	_	45	-	ns
TAVWH	taw	Address valid to end of write	35	_	40	_	45	_	ns
TAVWL	tas	Address Set-up Time	0	-	0	_	0	_	ns
TWLWH	twp	Write Pulse Width	35		40	_	45	_	ns
TWHAX	twn	Write Recovery Time	0		0	_	0	_	ns
TDVWH	tow	Data Valid to end of write	25	_	25	_	30	_	ns
TGHQZ	tHZ	Output high Z time (26, 27)	-	20	_	30	_	40	ns
TWHDX	toн	Data hold time (29)	0	-	0	_	0		ns
TWLQZ	twz	Write enable to output in high Z (26, 27)	_	20	_	30	-	40	ns
TWHQX	tow	Output active from end of write (26, 27, 29)	0	_	0	-	0	_	ns

Notes: 26. Transition is measured ± 500 mV from low or high impedance voltage with load (figures 1 and 2).

27. This parameter is guaranteed but not tested.
28. To access RAM CS = VIL.

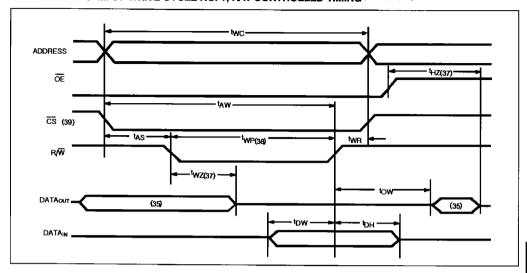
This condition must be valid for entire tsw time.

The specification for ton must be met by the device supplying write data to the RAM under all operating conditions.
 Although t_{DH} and t_{OW} values vary over voltage and temperature, the actual t_{DH} will always be smaller than the actual t_{OW}.

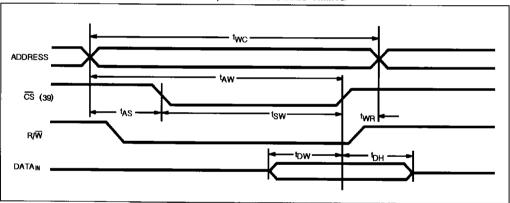
 STD symbol.

31. ALT symbol.

TIMING WAVEFORM OF WRITE CYCLE NO. 1, R/W CONTROLLED TIMING (32, 33, 34, 38)



TIMING WAVEFORM OF WRITE CYCLE NO. 2, CS CONTROLLED TIMING (32, 33, 34, 36)



- Notes: 32. RW must be high during all address transitions.

 - A write occurs during the overlap (tsw or twe) of a low \(\overlap{\overlap}\) and a low \(\overlap{\overlap}\).
 twa is measured from the earlier of \(\overlap{\overlap}\)S or \(\overlap{\overlap}\)W going high to the end of write cycle.

 - 35. During this period, the I/O pins are in the output state, and input signals must not be applied.

 36. If the CS low transition occurs simultaneously with or after the R/W low transition, the outputs remain in the high impedance state.
 - 37. Transition is measured ± 500 mV from steady state with a 5pF load (including scope and jig). This parameter is sampled and not 100 % tested.
 - 38. If $\overline{\text{OE}}$ is low during a R/W controlled write cycle, the write pulse width must be the larger of two or (twz + tow) to allow the I/O drivers to turn off and data to be placed on the bus for the required tow. If OE is high during an R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.
 - 39. To access RAM, CS = VIL.



AC PARAMETERS

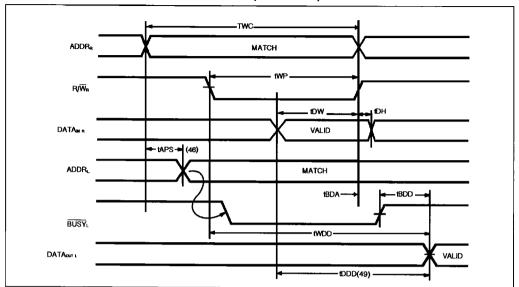
SYMBOL	PARAMETER	L 67132-45 L 67132-55 L 67142-55				L 67	UNIT	
BUSY TIMING (For L 67132 only)		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
tbaa	BUSY Access time to address	_	40		45		50	ns
t _{BDA}	BUSY Disable time to address	_	30	_	35	_	40	ns
t _{BAC}	BUSY Access time to Chip Select	_	40	_	45		50	ns
tBDC	BUSY Disable time to Chip Select	-	30		35		40	ns
twoo	Write Pulse to data delay (40)	_	70	_	80		90	ns
topo	Write data valid to read data delay (40)	_	45	_	55		70	ns
taps	Arbitration priority set-up time (41)	5		5		5	_	ns
teod	BUSY disable to valid data	_	Note 42		Note 42		Note 42	ns
BUSY TIM	ING (For L 67142 only)							ns
twa	Write to BUSY input (43)	0	-]	0	-	0	_	ns
tw _H	Write hold after BUSY (44)	20	_	20	_	20		ns
twoo	Write pulse to data delay (45)	-	70	-	80		90	ns
toop	Write data valid to read data delay (45)		45		55	_	70	ns

Notes: 40. Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveform of Read with BUSY (For L 67132 only)".

41. To ensure that the earlier of the two ports wins.

 41. To ensure that the earlier of the two posts whis.
 42. t_{BDD} is a calculated parameter and is the greater of 0, t_{WDD} - t_{WP} (actual) or t_{DDD} - t_{DW} (actual).
 43. To ensure that the write cycle is inhibited during contention.
 44. To ensure that a write cycle is completed after contention.
 45. Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveforms of Read with Port to port delay (For L 67142 and the content of only)".

TIMING WAVEFORM OF READ WITH BUSY (46, 47, 48) (FOR L 67132)



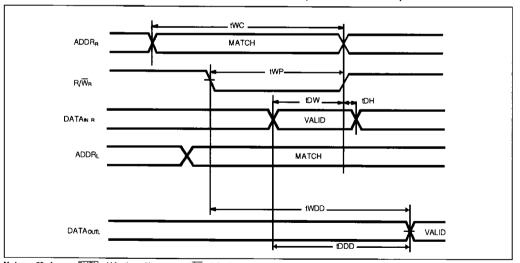
Notes: 46. To ensure that the earlier of the two port wins.

47. Write cycle parameters should be adhered to, to ensure proper writing.

48. Device is continuously enabled for both ports.

49. OE at L for the reading port.

TIMING WAVEFORM OF WRITE WITH PORT-TO-PORT (50, 51, 52) (FOR L 67142 ONLY)



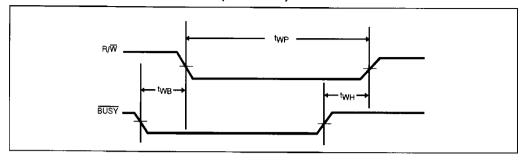
Notes: 50. Assume $\overline{BUSY} = H$ for the writing port, and $\overline{OE} = L$ for the reading port.

51. Write cycle parameters should be adhered to, to ensure proper writing.

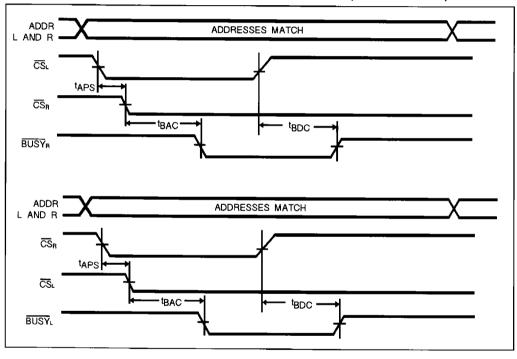
52. Device is continuously enabled for both ports.

4

TIMING WAVEFORM OF WRITE WITH BUSY (FOR L 67142)



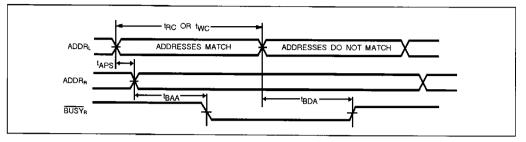
TIMING WAVEFORM OF CONTENTION CYCLE NO. 1, $\overline{\text{CS}}$ ARBITRATION (FOR L 67132 ONLY)



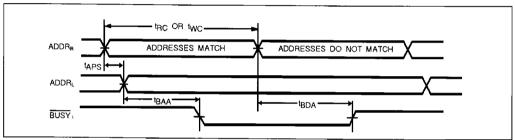


TIMING WAVEFORM OF CONTENTION CYCLE NO. 2, ADDRESS VALID ARBITRATION (FOR L 67132 ONLY) $^{\left(53\right)}$

LEFT ADDRESS VALID FIRST:

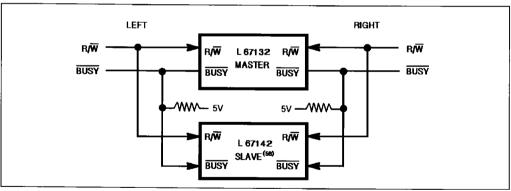


RIGHT ADDRESS VALID FIRST:



Note: 53. $\overline{CS}_L = \overline{CS}_R = V_{IL}$

16 BIT MASTER/SLAVE DUAL-PORT MEMORY SYSTEMS



Note: 54. No arbitration in L 67142 (SLAVE). BUSY-IN inhibits write in L 67142 (SLAVE).

ORDERING INFORMATION

